

**Search Notes**

Application/Control No.

10/816,450

Examiner

Benjamin P. Geib

Applicant(s)/Patent under  
Reexamination

CHUN ET AL.

Art Unit

2181

**SEARCHED**

Class	Subclass	Date	Examiner
345	503	9/26/2007	BPG
712	245	9/26/2007	BPG

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search	9/26/2007	BPG
NPL search (IEEE Xplore)	9/26/2007	BPG
Inventor name search	9/26/2007	BPG